

MILITARY SPECIFICATION

MICROCIRCUITS, DIGITAL, CMOS, COUNTERS/DIVIDERS,  
MONOLITHIC SILICON

Inactive for new design after 9 August 1996

This amendment forms a part of MIL-M-38510/56F, dated 19 February 1988,  
and is approved for use by all Departments and Agencies of the Department of Defense.

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Table I,  $I_{IH}$ , device types 01 - 55: Change max limits from "45" to "100" and "-45" to "-100".  
For the "-100" limit make the distinction " $I_{IL}$ " in the Symbol column.

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FIGURE 6, Device 03, 05, 53, 55, SW1: Change " $V_{DD1}$ " to " $V_{SS1}$ ".

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FIGURE 10. Switching time waveforms and test circuit – Continued,  $t_{PLH}$   $t_{PHL}$  Reset to output, Clock, device types 01, 02; Change limit for  $t_{PH}$  at  $25^{\circ}\text{C} \leq -55^{\circ}\text{C}$  from "500 ns" to "1.111  $\mu\text{s}$ " and for  $t_{PH}$  at  $\leq 125^{\circ}\text{C}$  from "750 ns" to "1.429  $\mu\text{s}$ ".

FIGURE 10. Switching time waveforms and test circuit – Continued,  $t_{PLH}$   $t_{PHL}$  Reset to output, Clock, device type 03; Change limit for  $t_{PH}$  at  $25^{\circ}\text{C} \leq -55^{\circ}\text{C}$  from "500 ns" to "588 ns" and for  $t_{PH}$  at  $\leq 125^{\circ}\text{C}$  from "750 ns" to "769 ns".

FIGURE 10. Switching time waveforms and test circuit – Continued,  $t_{PLH}$   $t_{PHL}$  Reset to output, Clock, device type 04; Change limit for  $t_{PH}$  at  $25^{\circ}\text{C} \leq -55^{\circ}\text{C}$  from "500 ns" to "1.111  $\mu\text{s}$ " and for  $t_{PH}$  at  $\leq 125^{\circ}\text{C}$  from "750 ns" to "1.429  $\mu\text{s}$ ".

FIGURE 10. Switching time waveforms and test circuit – Continued,  $t_{PLH}$   $t_{PHL}$  Reset to output, Clock, device type 05; Change limit for  $t_{PH}$  at  $25^{\circ}\text{C} \leq -55^{\circ}\text{C}$  from "300 ns" to "333 ns" and for  $t_{PH}$  at  $\leq 125^{\circ}\text{C}$  from "450 ns" to "455 ns".

FIGURE 10. Switching time waveforms and test circuit – Continued,  $t_{PLH}$   $t_{PHL}$  Reset to output, Reset, device type; Change from "51, 54"; to "52, 54".

FIGURE 10. Switching time waveforms and test circuit – Continued,  $t_{PLH}$   $t_{PHL}$  Reset to output, Clock, device type; Change from "51, 54"; to "52, 54", Change limit for  $t_{PH}$  at  $25^{\circ}\text{C} \leq -55^{\circ}\text{C}$  from "250 ns" to "503 ns" and for  $t_{PH}$  at  $\leq 125^{\circ}\text{C}$  from "350 ns" to "704 ns".

FIGURE 10. Switching time waveforms and test circuit – Continued,  $t_{PLH}$   $t_{PHL}$  Reset to output, Reset, device type; Change from "52"; to "51".

FIGURE 10. Switching time waveforms and test circuit – Continued,  $t_{PLH}$   $t_{PHL}$  Reset to output, Clock, device type; Change from "52"; to "51", Change limit for  $t_{PH}$  at  $25^{\circ}\text{C} \leq -55^{\circ}\text{C}$  from "500 ns" to "250 ns" and for  $t_{PH}$  at  $\leq 125^{\circ}\text{C}$  from "700 ns" to "350 ns".

FIGURE 10. Switching time waveforms and test circuit – Continued,  $t_{PLH}$   $t_{PHL}$  Reset to output, Clock, device type 53; Change limit for  $t_{PH}$  at  $25^{\circ}\text{C} \leq -55^{\circ}\text{C}$  from "335 ns" to "333 ns" and for  $t_{PH}$  at  $\leq 125^{\circ}\text{C}$  from "470 ns" to "455 ns".

FIGURE 10. Switching time waveforms and test circuit – Continued,  $t_{PLH}$   $t_{PHL}$  Reset to output, Clock, device type 55; Change limit for  $t_{PH}$  at  $25^{\circ}\text{C} \leq -55^{\circ}\text{C}$  from "200 ns" to "333 ns" and for  $t_{PH}$  at  $\leq 125^{\circ}\text{C}$  from "280 ns" to "455 ns".

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FSC 5962

AMSC N/A

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TABLE III,  $I_{IL}$ , Clock, Max limits column: Change “-1.0” and “-45.0” to “-100.0” and “-100.0” respectively.  
TABLE III,  $I_{IL}$ , Reset, Max limits column: Change “-1.0” and “-45.0” to “-100.0” and “-100.0” respectively.  
TABLE III,  $I_{IH}$ , Clock, Max limits column: Change “-1.0” and “-45.0” to “-100.0” and “-100.0” respectively.  
TABLE III,  $I_{IH}$ , Reset, Max limits column: Change “1.0” and “45.0” to “100.0” and “100.0” respectively.

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TABLE VIII, Threshold-voltage test conditions; Delete and replace with the following:

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Device type	GND	10 V	V <sub>TN</sub> measured at		GND	-10 V	V <sub>TP</sub> measured at	
			-20 $\mu$ A supply	-10 $\mu$ A supply			10 $\mu$ A supply	10 $\mu$ A supply
01 51	15	16		8, 13, 14	15	8		13, 14, 16
02 52	15	16		1, 2, 3, 7-10, 12, 14	15	1, 2, 3, 7-10, 12, 14		16
03 53	10	8, 11		8, 11	11	16		16
04 54	14	13, 15, 16		8	14	8, 13, 15		16
05 55	1	14		2, 7	1	2, 7		14

“

CONCLUDING MATERIAL

Custodians:

Army - CR  
Navy - EC  
Air Force - 11  
NASA - NA  
DLA - CC

Preparing activity:

DLA - CC

Review activities:

Navy - AS, CG, MC, OS, SH  
Army - AR, MI, SM  
Air Force - 19, 85, 99

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